Abstracts

On-Wafer Measurement of Microstrip-Based MIMICs Without via Holes

G. Strauss, P. Ehret and W. Menzel. "On-Wafer Measurement of Microstrip-Based MIMICs Without via Holes." 1996 MTT-S International Microwave Symposium Digest 96.3 (1996 Vol. III [MWSYM]): 1399-1402.

Typically, on-wafer measurements of microstrip based MMICs require via holes ground contacts. To avoid these, the design of ground contacts for on-wafer probing at mm-wave frequencies using electromagnetic field coupling is presented in this paper. Theoretical and experimental results of the respective transitions are given as well as a test deembedding this transition from the behaviour of a transmission line.

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